

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/044,920	PIASIO ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Christopher L. Chin	1641

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner
Same as	above	7/31/2005	CC